DDR SDRAM Specification Version 0.7



Revision History

Version 0.0 (May, 2000)

- Prototype 512Mb specification
- DC current is "TBD" and will be defined from M-die

Version 0.1(Apr,2001)

- Added DC target spec values
- Deleted tDAL in AC parameter X
- Changed V_{ID}(DC), Input differential voltage, CK and $\overline{\text{CK}}$ inputs min. from 0.3V to 0.36V.
- Added $V_{IX}(DC)$, Input crossing point voltage, CK and \overline{CK} inputs to 1.15V ~1.35V.
- Added Output high/low current(I_{OH},I_{OL}) for half strength driver.
- Added Pullup current to pulldown current ratio to 0.71 ~ 1.4.
- Changed V_{ID}(AC), Input differential voltage, CK and $\overline{\text{CK}}$ inputs min. from 0.62V to 0.7V.
- Changed tCK max from 15ns to 12ns for all speed binning.
- Changed tDQSH/tDQSL min. from 0.4tCK to 0.35tCK.
- Added tHZ/tLZ(Data-out high/Low impedence time from CK/CK)
- Added tQHS(Data hold skew factor)
- Added tDSS/tDSH(DQS falling edge to/from CK rising setup/hold time)
- Added overshoot/undershoot spec
- Added tSL(I), tSL(IO), tSL(O)

Parameter	Definition	Value Min. Max.		Unit
Farameter	Delilillion			Offit
tSL(I)	Input Slew Rate(for input only)	0.5		V/ns
tSL(IO)	Input Slew Rate(for I/O pins)	0.5		V/ns
tSL(O)	Output Slew Rate(x4,x8)	1.0	4.5	V/ns
tSL(O)	Output Slew Rate(x16)	0.7	5	V/ns

- Changed from supporting QFC function to not supporting QFC function(Deleted all QFC function supported)
- Changed name and specification from IDD7 to IDD7A

Description	from	to
Orerating current - Four bank operation	IDD7(50% of data changing at every burst)	IDD7A(100% of data changing at every burst)

Version 0.2(July,2001)

- Changed the target spec. to preliminary spec.
- Updated the DC current
- Updated the table at page#29

Version 0.3(August,2001)

- Changed the DC current

Version 0.4(October,2001)

- Modificated typo.
- Changed pin # 17 from NC to A13 in Package pinout.
- Revised "Write with autoprecharge" table in page 29.
- Added tIS and tPDEX parameters in "power down" timing of page 31.
- Revised "Absolute maximum rating" table in page 38.
 - . Changed "Voltage on VDDQ supply relative to VSS" value from -0.5~3.6V to -1~3.6V
- . Changed "power dissipation" value from 1.0W to 1.5W.
- Revised AC parameter table



		From							T	ō		
	DDR	DDR266A		DDR266A DDR266B DDR200 DDR26		266A DDR266B		DDR200				
	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.
tHZ(DQ)	tACmin -400ps	tACmax -400ps	tACmin -400ps	tACmax -400ps	tACmin -400ps	tACmax -400ps	-0.75	+0.75	-0.75	+0.75	-0.8	+0.8
tLZ(DQ)	tACmin -400ps	tACmax -400ps	tACmin -400ps	tACmax -400ps	tACmin -400ps	tACmax -400ps	-0.75	+0.75	-0.75	+0.75	-0.8	+0.8
tHZ(DQS)							-0.75	+0.75	-0.75	+0.75	-0.8	+0.8
tLZ(DQS)							-0.75	+0.75	-0.75	+0.75	-1.1	-0.8
tWPST (tCK)	0.25		0.25		0.25		0.4	0.6	0.4	0.6	0.4	0.6
tPDEX	10ns		10ns		10ns		7.5ns		7.5ns		10ns	

Version 0.5(November,2001)

- Deleted tHZ/tLZ of DQS

Version 0.6(November,2001)

- Deleted typical current in IDD spec. table
- Included address and control input setup/hold time(tIS/tIH) at slow slew rate in DDR200/266 AC specification
- Deleted Exit self refresh to write command(tXSW) in DDR200/266 AC specification
- Rename tXSA(exit self refresh to bank active command) to tXSNR(exit self refresh to non read command) at DDR200/266
- Rename tXSR(exit self refresh to read command) to tXSRD at DDR200/266
- Rename tWPREH(DQS in hold time) to tWPRE at DDR200/266
- Rename tREF(Refresh interval time) to tREFI at DDR200/266
- Added tDAL(tWR+tRP)
- Updated current value

Version 0.7(May,2002)

- Changed the preliminary spec. to final spec
- Corrected typo in package pinout



Contents	
Revision History	2
General Information	7
1. Key Features	8
1.1 Features	8
1.2 Operating Frequencies	8
2. Package Pinout & Dimension	9
2.1 Package Pintout	9
2.2 Input/Output Function Description	10
2.3 66 Pin TSOP(II)/MS-024FC Package Physical Dimension	11
2 Functional Description	12
3. Functional Description	
3.1 Simplified State Diagram	12
3.2 Basic Functionality	13
3.2.1 Power-Up Sequence	13
3.2.2 Mode Register Definition	14
3.2.2.1 Mode Register Set(MRS)	14
3.2.2.2 Extended Mode Register Set(EMRS)	16
3.2.3 Precharge	17
3.2.4 No Operation(NOP) & Device Deselect 3.2.5 Row Active	17 18
	_
3.2.6 Read Bank 3.2.7 Write Bank	18 18
3.3 Essential Functionality for DDR SDRAM	19
3.3.1 Burst Read Operation	19
3.3.2 Burst Write Operation	20
3.3.3 Read Interrupted by a Read	21
3.3.4 Read Interrupted by a Write & Burst Stop	21
3.3.5 Read Interrupted by a Precharge	22
3.3.6 Write Interrupted by a Write	23



3.3.7 Write Interrupted by a Read & DM	24			
3.3.8 Write Interrupted by a Precharge & DM	25			
3.3.9 Burst Stop	26			
3.3.10 DM masking	27			
3.3.11 Read With Auto Precharge	28			
3.3.12 Write With Auto Precharge	29			
3.3.13 Auto Refresh & Self Refresh	30			
3.3.14 Power Down	31			
4. Command Truth Table	32			
5. Functional Truth Table	33			
6. Absolute Maximum Rating	38			
7. DC Operating Conditions & Specifications	38			
7.1 DC Operating Conditions	38			
7.2 DC Specifications	39			
8. AC Operating Conditions & Timming Specification	42			
8.1 AC Operating Conditions	42			
8.2 AC Overshoot/Undershoot specification	43			
8.2.1 Overshoot/Undershoot specification for Address and Control Pins	43			
8.2.2 Overshoot/Undershoot specification for Data Pins	44			
8.3 AC Timming Parameters & Specification	45			
9. AC Operating Test Conditions	48			
10. Input/Output Capacitance	48			
11. IBIS: I/V Characteristics for Input and Output Buffers	49			
11.1 Normal strength driver	49			
11.2 Half strength driver	50			
Timing Diagram				



List of tables

Table 1 : Operating frequency and DLL jitter	8
Table 2. : Column address configurtion	9
Table 3 : Input/Output function description	10
Table 4: Burst address ordering for burst length	15
Table 5 : Bank selection for precharge by bank address bits	17
Table 6 : Operating description when new command asserted while	
read with auto precharge is issued	28
Table 7 : Operating description when new command asserted while	
write with auto precharge is issued	29
Table 8 : Command truth table	32
Table 9-1 : Functional truth table	33
Table 9-2 : Functional truth table (contined)	34
Table 9-3 : Functional truth table (contined)	35
Table 9-4 : Functional truth table (contiued)	36
Table 9-5 : Functional truth table (cotinued)	37
Table 10 : Absolute maximum raings	38
Table 11 : DC operating condtion	38
Table 12 : DC specification	41
Table 13 : AC operating condition	42
Table 14: Overshoot/Undershoot specification for Address and Control Pins	43
Table 15 : Overshoot/Undershoot specification for Data Pins	44
Table 16 : AC timing parameters and specifications	45
Table 17 : AC operating test conditions	48
Table 18 : Input/Output capacitance	48
Table 19 : Pull down and pull up current values(For normal strength driver)	50
Table 20 : Pull down and pull up current values(For half strength driver)	52



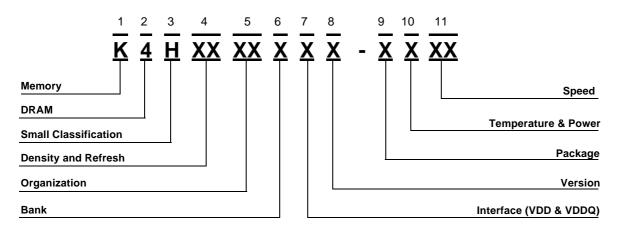
List of figures

Figure 1 : 512Mb Package Pinout	9
Figure 2 : Package dimension	11
Figure 3 : State digram	12
Figure 4 : Power up and initialization sequence	13
Figure 5 : Mode register set	14
Figure 6 : Mode register set sequence	15
Figure 7 : Extend mode register set	16
Figure 8 : Bank activation command cycle timing	18
Figure 9 : Burst read operation timing	19
Figure 10 : Burst write operation timing	20
Figure 11 : Read interrupted by a read timing	21
Figure 12 : Read interrupted by a write and burst stop timing	21
Figure 13: Read interrupted by a precharge timing	22
Figure 14: Write interrupted by a write timing	23
Figure 15 : Write interrupted by a read and DM timing	24
Figure 16: Write interrupted by a precharge and DM timing	25
Figure 17: Burst stop timing	26
Figure 18 : DM masking timing	27
Figure 19 : Read with auto precharge timing	28
Figure 20: Write with auto precharge timing	29
Figure 21 : Auto refresh timing	30
Figure 22 : Self refresh timing	30
Figure 23: Power down entry and exit timing	31
Figure 24 : AC overshoot/Undershoot Definition	43
Figure 25 : AC overshoot/Undershoot Definition	44
Figure 26 : Output Load Circuit (SSTL_2)	48
Figure 27: I / V characteristics for input/output buffers(For normal strength driver):	
pull-up(above) and pull-down(below)	49
Figure 28: I / V characteristics for input/output buffers(For half strength driver):	
pull-up(above) and pull-down(below)	51



General Information

Organization	133Mhz w/ CL=2	133Mhz w/ CL=2.5	100Mhz w/ CL=2
128Mx4	K4H510438M-TCA2	K4H510438M-TCB0	K4H510438M-TCA0
12010184	K4H510438M-TLA2	K4H510438M-TLB0	K4H510438M-TLA0
64Mx8	K4H510838M-TCA2	K4H510838M-TCB0	K4H510838M-TCA0
OHIVIXO	K4H510838M-TLA2	K4H510838M-TLB0	K4H510838M-TLA0



1. SAMSUNG Memory: K

2. DRAM: 4

3. Small Classification

H : DDR SDRAM

4. Density & Refresh

64 : 64M 4K/64ms 28 : 128M 4K/64ms 56 : 256M 8K/64ms 51 : 512M 8K/64ms 1G : 1G 16K/32ms

5. Organization

04 : x4 08 : x8 16 : x16 32 : x32

6. Bank

3:4 Bank

7. Interface (VDD & VDDQ)

8: SSTL-2(2.5V, 2.5V)

8. Version

M: 1st Generation
A: 2nd Generation
B: 3rd Generation
C: 4th Generation
D: 5th Generation
E: 6th Generation

9. Package

T: TSOP2 (400mil x 875mil)

10. Temperature & Power

C: (Commercial, Normal)L: (Commercial, Low)

11. Speed

A0:10ns@CL2 A2:7.5ns@CL2 B0:7.5ns@CL2.5



1. Key Features

1.1 Features

- Double-data-rate architecture; two data transfers per clock cycle
- Bidirectional data strobe(DQS)
- Four banks operation
- Differential clock inputs(CK and CK)
- DLL aligns DQ and DQS transition with CK transition
- · MRS cycle with address key programs
 - -. Read latency 2, 2.5 (clock)
 - -. Burst length (2, 4, 8)
 - -. Burst type (sequential & interleave)
- All inputs except data & DM are sampled at the positive going edge of the system clock(CK)
- Data I/O transactions on both edges of data strobe
- Edge aligned data output, center aligned data input
- DM for write masking only
- · Auto & Self refresh
- 7.8us refresh interval(8K/64ms refresh)
- Maximum burst refresh cycle: 8
- 66pin TSOP II package

1.2 Operating Frequencies

	- A2(DDR266A)	- B0(DDR266B)	- A0(DDR200)
Speed @CL2	133MHz	100MHz	100MHz
Speed @CL2.5	133MHz	133MHz	-
DLL jitter	±0.75ns	±0.75ns	±0.8ns

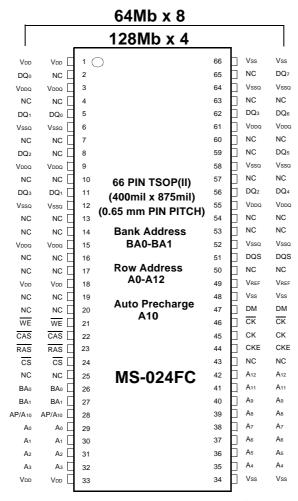
*CL: Cas Latency

Table 1. Operating frequency and DLL jitter



2. Package Pinout & Dimension

2.1 Package Pinout



Flgure 1. 256Mb package Pinout

Organization	Column Address
128Mx4	A0-A9, A11,A12
64Mx8	A0-A9,A11

DM is internally loaded to match DQ and DQS identically.

Table 2. Column address configuration



2.2 Input/Output Function Description

SYMBOL	TYPE	DESCRIPTION	
CK, CK	Input	Clock: CK and $\overline{\text{CK}}$ are differential clock inputs. All address and control input signals are sampled on the positive edge of CK and negative edge of $\overline{\text{CK}}$. Output (read) data is referenced to both edges of CK. Internal clock signals are derived from $\overline{\text{CK/CK}}$.	
CKE	Input	Clock Enable: CKE HIGH activates, and CKE LOW deactivates internal clock signals, and device input buffers and output drivers. Deactivating the clock provides PRECHARGE POWER-DOWN and SELF REFRESH operation (all banks idle), or ACTIVE POWER-DOWN (row ACTIVE in any bank). CKE is synchronous for all functions except for disabling outputs, which is achieved asynchronously. Input buffers, excluding CK, CK and CKE are disabled during power-down and self refresh modes, providing low standby power. CKE will recognize an LVCMOS LOW level prior to VREF being stable on power-up.	
CS	Input	Chip Select: CS enables(registered LOW) and disables(registered HIGH) the command decoder. All commands are masked when CS is registered HIGH. CS provides for external bank selection on systems with multiple banks. CS is considered part of the command code.	
RAS, CAS, WE	Input	Command Inputs : RAS, CAS and WE (along with CS) define the command being entered.	
LDM,(U)DM	Input	Input Data Mask: DM is an input mask signal for write data. Input data is masked when DM is sampled HIGH along with that input data during a WRITE access. DM is sampled on both edges of DQS. DM pins include dummy loading internally, to matches the DQ and DQS loading. For the x16, LDM corresponds to the data on DQ0-DQ7; UDM correspons to the data on DQ8-DQ15.	
BA0, BA1	Input	Bank Addres Inputs: BA0 and BA1 define to which bank ACTIVE, READ, WRITE or PRE-CHARGE command is being applied.	
A [n : 0]	Input	Address Inputs: Provide the row address for ACTIVE commands, the column address and AUTO PRECHARGE bit for READ/WRITE commands, to select one location out of the memory array in the respective bank. A10 is sampled during a PRECHARGE command to determine whether the PRECHARGE applies to one bank (A10 LOW) or all banks (A10 HIGH). If only one bank is to be precharged, the bank is selected by BA0, BA1. The address inputs also provide the op-code during a MODE REGISTER SET command. BA0 and BA1 define which mode register is loaded during the MODE REGISTER SET command (MRS or EMRS).	
DQ	I/O	Data Input/Output : Data bus	
LDQS,(U)DQS	I/O	Data Strobe: Output with read data, input with write data. Edge-aligned with read data, centered in write data. Used to capture write data. For the x16, LDQS corresponds to the data on DQ0-DQ7; UDQS corresponds to the data on DQ8-DQ15.	
NC	-	No Connect : No internal electrical connection is present.	
VDDQ	Supply	DQ Power Supply: +2.5V ± 0.2V.	
VssQ	Supply	DQ Ground.	
VDD	Supply	Power Supply : $+2.5V \pm 0.2V$ (device specific).	
Vss	Supply	Ground.	
VREF	Input	SSTL_2 reference voltage.	

Table 3. Input/Output Function Description



2.3 66 Pin TSOP(II)/MS-024FC Package Physical Dimension

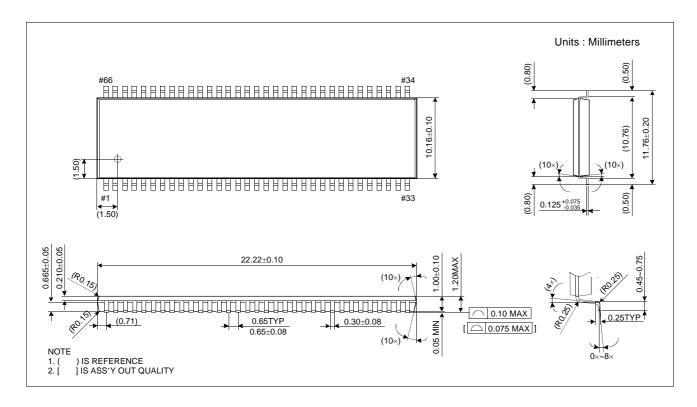


Figure 2. Package dimension

3. Functional Description

3.1 Simplified State Diagram

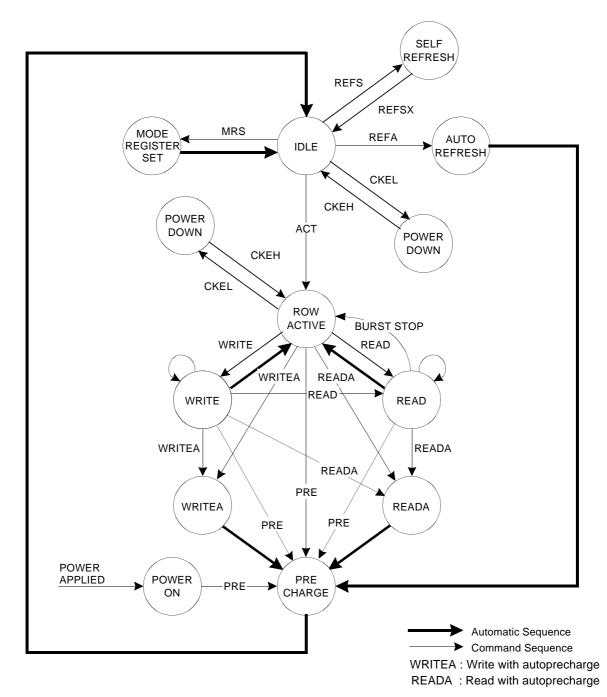


Figure 3. State diagram



3.2 Basic Functionality

3.2.1 Power-Up and Initialization Sequence

The following sequence is required for POWER UP and Initialization.

- 1. Apply power and attempt to maintain CKE at a low state(all other inputs may be undefined.)
 - Apply VDD before or at the same time as VDDQ.
 - Apply VDDQ before or at the same time as VTT & Vref.

No power sequencing is specified during power up or power down given the following criteria:

- VDD and VDDQ are driven from a single power converter output, and
- VTT is limited to 1.44V (reflecting VDDQ(max)/2 + 50mV VREF variation +40m V VTT variation), and
- VREF tracks VDDQ/2, and
- A minimum resistance of 42 ohms(22 ohm series resistor + 22 ohm parallel resistor 5% tolerance) limits the input current from the V⊤⊤ supply into any pin.

If the above criteria cannot be met by the system design, the following table must be adhered to during power up:

Voltage Description	Sequencing	Voltage Relationship to avoid latch-up
VDDQ	After or with VDD	<vdd +="" 0.3v<="" td=""></vdd>
VTT	After or with VDDQ	< VDDQ +0.3V
VREF	After or with VDDQ	<vddq +0.3v<="" td=""></vddq>

- 2. Start clock and maintain stable condition for a minimum of 200us.
- 3. The minimum of 200us after stable power and clock(CK, CK), apply NOP & take CKE high.
- 4. Issue precharge commands for all banks of the device.
- 5. Issue EMRS to enable DLL.(To issue "DLL Enable" command, provide "Low" to A0, "High" to BA0 and "Low" to all of the rest address pins, A1~A11 and BA1)
- 6. Issue a mode register set command for "DLL reset". The additional 200 cycles of clock input is required to lock the DLL. (To issue DLL reset command, provide "High" to A8 and "Low" to BA0)
- ^{*1} 7. Issue precharge commands for all banks of the device.
 - 8. Issue 2 or more auto-refresh commands.
 - 9. Issue a mode register set command with low to A8 to initialize device operation.
 - *1 Sequence of 6 & 7 is regardless of the order.

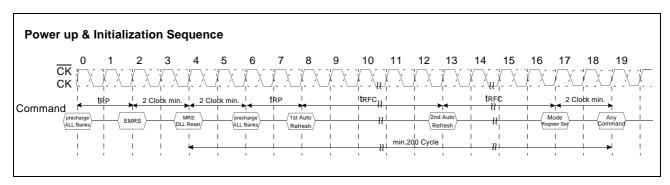


Figure 4. Power up and initialization sequence



3.2.2 Mode Register Definition

3.2.2.1 Mode Register Set(MRS)

The mode register stores the data for controlling the various operating modes of DDR SDRAM. It programs CAS latency, addressing mode, burst length, test mode, DLL reset and various vendor specific options to make DDR SDRAM useful for variety of different applications. The default value of the mode register is not defined, therefore the mode register must be written after EMRS setting for proper DDR SDRAM operation. The mode register is written by asserting low on CS, RAS, CAS, WE and BA0(The DDR SDRAM should be in all bank precharge with CKE already high prior to writing into the mode register). The states of address pins A0 ~ A12 in the same cycle as CS, RAS, CAS, WE and BA0 going low are written in the mode register. Two clock cycles are requested to complete the write operation in the mode register. The mode register contents can be changed using the same command and clock cycle requirements during operation as long as all banks are in the idle state. The mode register is divided into various fields depending on functionality. The burst length uses A0 ~ A2, addressing mode uses A3, CAS latency(read latency from column address) uses A4 ~ A6. A7 is used for test mode. A8 is used for DLL reset. A7 must be set to low for normal MRS operation. Refer to the table for specific codes for various burst lengths, addressing modes and CAS latencies.

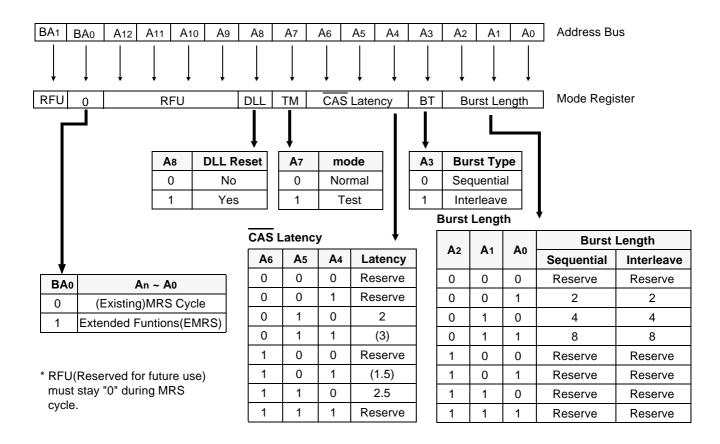


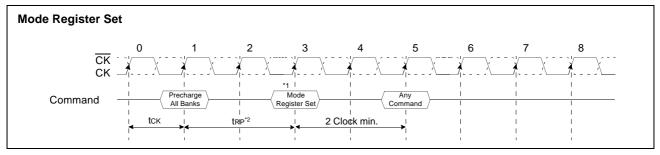
Figure 5. Mode Register Set



Burst Address Ordering for Burst Length

Burst Length	Starting Address(A2, A1, A0)	Sequential Mode	Interleave Mode
2	xx0	0, 1	0, 1
2	xx1	1, 0	1, 0
	x00	0, 1, 2, 3	0, 1, 2, 3
4	x01	1, 2, 3, 0	1, 0, 3, 2
4	x10	2, 3, 0, 1	2, 3, 0, 1
	x11	3, 0, 1, 2	3, 2, 1, 0
	000	0, 1, 2, 3, 4, 5, 6, 7	0, 1, 2, 3, 4, 5, 6, 7
	001	1, 2, 3, 4, 5, 6, 7, 0	1, 0, 3, 2, 5, 4, 7, 6
	010	2, 3, 4, 5, 6, 7, 0, 1	2, 3, 0, 1, 6, 7, 4, 5
8	011	3, 4, 5, 6, 7, 0, 1, 2	3, 2, 1, 0, 7, 6, 5, 4
0	100	4, 5, 6, 7, 0, 1, 2, 3	4, 5, 6, 7, 0, 1, 2, 3
	101	5, 6, 7, 0, 1, 2, 3, 4	5, 4, 7, 6, 1, 0, 3, 2
	110	6, 7, 0, 1, 2, 3, 4, 5	6, 7, 4, 5, 2, 3, 0, 1
	111	7, 0, 1, 2, 3, 4, 5, 6	7, 6, 5, 4, 3, 2, 1, 0

Table 4. Burst address ordering for burst length



^{*1 :} MRS can be issued only at all bank precharge state.

Figure 6. Mode Register Set sequence



 $[\]ensuremath{^{*}2}$: Minimum tRP is required to issue MRS command.

3.2.2.2 Extended Mode Register Set(EMRS)

The extended mode register stores the data for enabling or disabling DLL and selecting output driver size. The default value of the extended mode register is not defined, therefore the extended mode register must be written after power up for enabling or disabling DLL. The extended mode register is written by asserting low on CS, RAS, CAS, WE and high on BA0(The DDR SDRAM should be in all bank precharge with CKE already high prior to writing into the extended mode register). The state of address pins A0 ~ A11 and BA1 in the same cycle as CS, RAS, CAS and WE going low are written in the extended mode register. Two clock cycles are required to complete the write operation in the extended mode register. The mode register contents can be changed using the same command and clock cycle requirements during operation as long as all banks are in the idle state. A0 is used for DLL enable or disable. "High" on BA0 is used for EMRS. All the other address pins except A0 and BA0 must be set to low for proper EMRS operation. Refer to the table for specific codes.

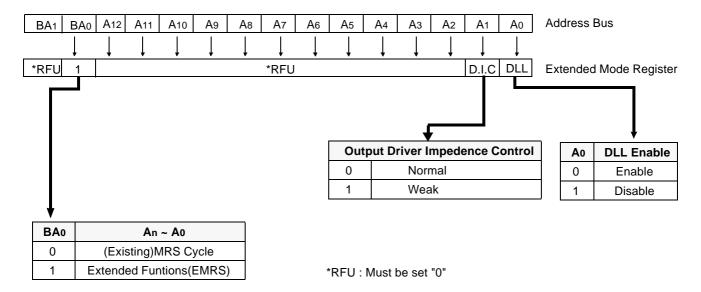


Figure 7. Extend Mode Register set

DLL Enable/Disable

The DLL must be enabled for normal operation. DLL enable is required during power-up initialization, and upon returing to normal operation after having disabled the DLL for the purpose of debug or evaluation (upon exiting Self Refresh Mode, the DLL is enabled automatically). Any time the DLL is enabled, 200 clock cycles must occur before a READ command can be issued.

Output Drive Strength

The normal drive strength for all outputs is specified to be SSTL_2, Class II. Samsung supports a weak driver strength option, intended for lighter load and/or point-to-point environments. I-V curves for the normal drive strength and weak drive strength are included in 11.1~2 of this document.



3.2.3 Precharge

The precharge command is used to precharge or close a bank that has been activated. The precharge command is issued when CS, RAS and WE are low and CAS is high at the rising edge of the clock. The precharge command can be used to precharge each bank respectively or all banks simultaneously. The bank select addresses(BA0, BA1) are used to define which bank is precharged when the command is initiated. For write cycle, tWR(min.) must be satisfied until the precharge command can be issued. After tRP from the precharge, an active command to the same bank can be initiated.

A10/AP BA1 BA0 Precharge 0 0 0 Bank A Only 0 1 Bank B Only 0 0 1 0 Bank C Only 0 Bank D Only 1 1 1 Χ Χ All Banks

Bank Selection for Precharge by Bank address bits

Table 5. Bank selection for precharge by Bank address bits

3.2.4 No Operation(NOP) & Device Deselect

The device should be deselected by deactivating the $\overline{\text{CS}}$ signal. In this mode DDR SDRAM should ignore all the control inputs. The DDR SDRAMs are put in NOP mode when $\overline{\text{CS}}$ is active and by deactivating RAS, CAS and WE. For both Deselect and NOP the device should finish the current operation when this command is issued.



3.2.5 Row Active

The Bank Activation command is issued by holding CAS and WE high with CS and RAS low at the rising edge of the clock(CK). The DDR SDRAM has four independent banks, so two Bank Select addresses(BA0, BA1) are required. The Bank Activation command must be applied before any Read or Write operation is executed. The delay from the Bank Activation command to the first read or write command must meet or exceed the minimum of RAS to CAS delay time(tRCD min). Once a bank has been activated, it must be precharged before another Bank Activation command can be applied to the same bank. The minimum time interval between interleaved Bank Activation commands(Bank A to Bank B and vice versa) is the Bank to Bank delay time(tRRD min).

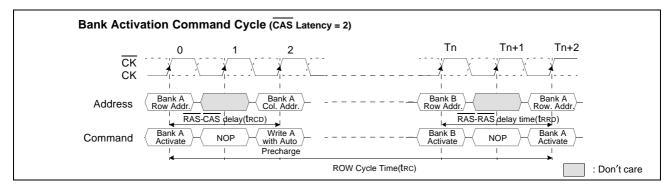


Figure 8. Bank activation command cycle timing

3.2.6 Read Bank

This command is use<u>d after the row activate command to initiate the burst read of data.</u> The read command is initiated by activating RAS, CS, CAS, and deasserting WE at the same clock sampling(rising) edge as described in the command truth table. The length of the burst and the CAS latency time will be determined by the values programmed during the MRS command.

3.2.7 Write Bank

This command is used afte<u>r the row activate command</u> to initiate the burst write of data. The write command is initiated by activating RAS, CS, CAS, and WE at the same clock sampling(rising) edge as described in the command truth table. The length of the burst will be determined by the values programmed during the MRS command.

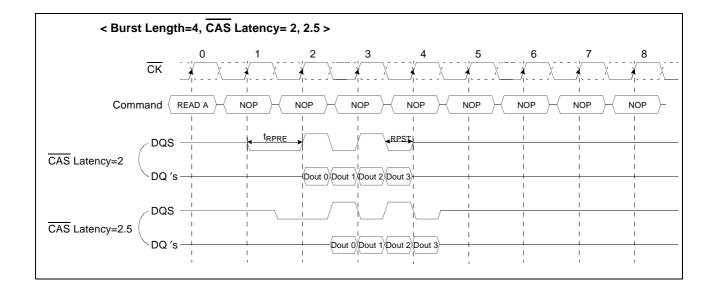


3.3 Essential Functionality for DDR SDRAM

The essential functionality that is required for the DDR SDRAM device is described in this chapter

3.3.1 Burst Read Operation

Burst Read operation in DDR SDRAM is <u>in the</u> same manner as <u>the current SD</u>RAM such that the Burst read command is issued by asserting CS and CAS low while holding RAS and WE high at the rising edge of the clock(CK) after tRCD from the bank activation. The address inputs (A0~A9) determine the starting address for the Burst. The Mode Register sets type of burst(Sequential or interleave) and burst length(2, 4, 8). The first output data is available after the CAS Latency from the READ command, and the consecutive data are presented on the falling and rising edge of Data Strobe(DQS) adopted by DDR SDRAM until the burst length is completed.





3.3.2 Burst Write Operation

The Burst Write command is issued by having \overline{CS} , \overline{CAS} , and \overline{WE} low while holding \overline{RAS} high at the rising edge of the clock(CK). The address inputs determine the starting column address. There is no write latency relative to DQS required for burst write cycle. The first data of a burst write cycle must be applied on the DQ pins tDS(Data-in setup time) prior to data strobe edge enabled after tDQSS from the rising edge of the clock(CK) that the write command is issued. The remaining data inputs must be supplied on each subsequent falling and rising edge of Data Strobe until the burst length is completed. When the burst has been finished, any additional data supplied to the DQ pins will be ignored.

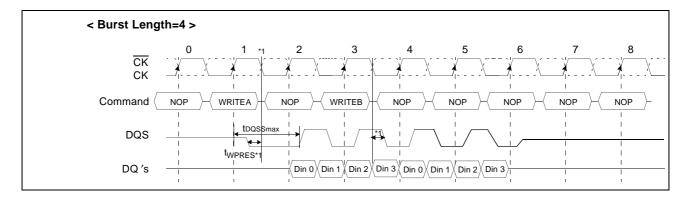


Figure 10. Burst write operation timing

1. The specific requirement is that DQS be valid(High or Low) on or before this CK edge. The case shown (DQS going from High_Z to logic Low) applies when no writes were previously in progress on the bus. If a previous write was in progress, DQS could be High at this time, depending on tDQSS.



3.3.3 Read Interrupted by a Read

A Burst Read can be interrupted before completion of the burst by new Read command of any bank. When the previous burst is interrupted, the remaining addresses are overridden by the new address with the full burst length. The data from the first Read command continues to appear on the outputs until the CAS latency from the interrupting Read command is satisfied. At this point the data from the interrupting Read command appears. Read to Read interval is minimum 1 Clock.

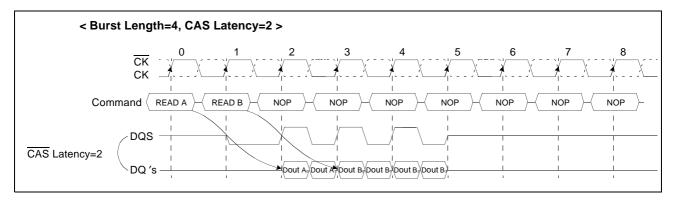


Figure 11. Read interrupted by a read timing

3.3.4 Read Interrupted by a Write & Burst Stop

To interrupt a burst read with a write command, Burst Stop command must be asserted to avoid data contention on the I/O bus by placing the DQ's(Output drivers) in a high impedance state. To insure the DQ's are tristated one cycle before the beginning the write operation, Burst stop command must be applied at least 2 clock cycles for CL=2 and at least 3 clock cycles for CL=2.5 before the Write command.

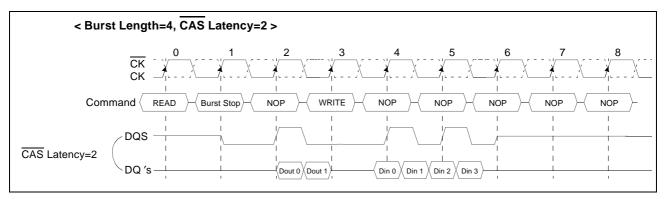


Figure 12. Read interrupted by a write and burst stop timing.

The following functionality establishes how a Write command may interrupt a Read burst.

- For Write commands interrupting a Read burst, a Burst Terminate command is required to stop the read burst and tristate the DQ bus prior to valid input write data. Once the <u>Burst Terminate command has been</u> issued, the minimum delay to a Write command = RU(CL) [CL is the CAS Latency and RU means round up to the nearest integer].
- 2. It is illegal for a Write command to interrupt a Read with autoprecharge command.



A Burst Read operation can be interrupted by precharge of the same bank. The minimum 1 clock is required for the read to precharge intervals. A precharge command to output disable latency is equivalent to the latency.

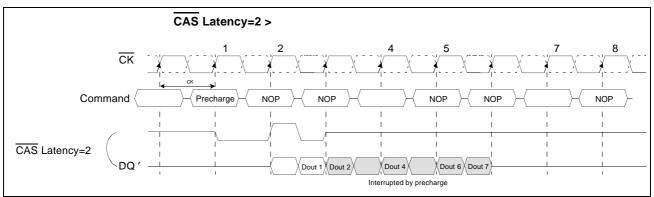


Figure 13. Read interrupted by a precharge timing

When a burst Read command is issued to a DDR SDRAM, a Precharge command may be issued to the same bank before the Read burst is complete. The following functionality determines when a Precharge command

1. For the earliest possible Precharge command without interrupting a Read burst, the Precharge command is the CAS

Precharge time).

the rising <u>clock</u> edge which is CL clock cycles before the last data from the interrupted Read burst where CL is the Latency. Once the last data word has been output, the output buffers are tristated. A new Bank Activate command may be issued to the same bank after tRP.

For a Read with autoprecharge command, a new Bank Activate command may be issued to the same bank after tRP where tRP begins on the rising clock edge which is CL clock cycles before the end of the CAS Latency. During Read with autoprecharge, the initiation of the internal

precharge operation without interrupting the Read burst as described in 1 above.

 clock cycles between a Precharge command and a new Bank Activate command to the same bank equals tRP/tCK (where tCK is the clock cycle time) with the result rounded up to the nearest integer number of

can only be given on a rising

In all cases, a Precharge operation cannot be initiated unless tRAS(min) [minimum Bank Activate to Precharge time] has been satisfied. This includes Read with autoprecharge commands where tRAS(min) must still be

the earliest possible Precharge command which does not interrupt the burst.



3.3.6 Write Interrupted by a Write

A Burst Write can be interrupted before completion of the burst by a new Write command, with the only restriction that the interval that separates the commands must be at least one clock cycle. When the previous burst is interrupted, the remaining addresses are overridden by the new address and data will be written into the device until the programmed burst length is satisfied.

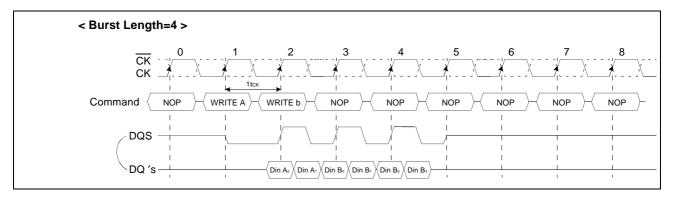


Figure 14. Write interrupted by a write timing



3.3.7 Write Interrupted by a Read & DM

A burst write can be interrupted by a read command of any bank. The DQ's must be in the high impedance state at least one clock cycle before the interrupting read data appear on the outputs to avoid data contention. When the read command is registered, any residual data from the burst write cycle must be masked by DM. The delay from the last data to read command (tCDLR) is required to avoid the data contention DRAM inside. Data that are presented on the DQ pins before the read command is initiated will actually be written to the memory. Read command interrupting write can not be issued at the next clock edge of that of write command.

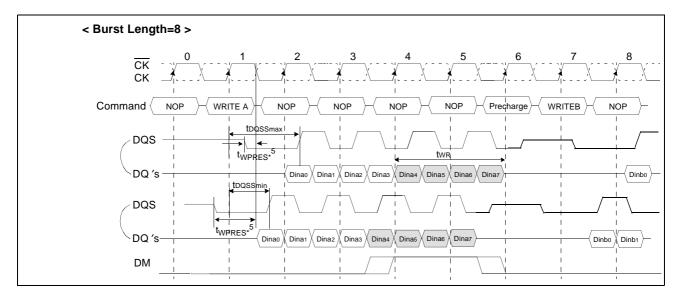


Figure 15. Write interrupted by a read and DM timing

The following function established how a Read command may interrupt a Write burst and which input data is not written into the memory.

- 1. For Read commands interrupting a Write burst, the minimum Write to Read command delay is 2 clock cycles. The case where the Write to Read delay is 1 clock cycle is disallowed
- 2. For Read commands interrupting a Write burst, the DM pin must be used to mask the input data words which immediately precede the interrupting Read operation and the input data word which immediately follows the interrupting Read operation
- 3. For all cases of a Read interrupting a Write, the DQ and DQS buses must be released by the driving chip (i.e., the memory controller) in time to allow the buses to turn around before the DDR SDRAM drives them during a read operation.
- 4. If input Write data is masked by the Read command, the DQS input is ignored by the DDR SDRAM.
- 5. Refer to "3.3.2 Burst write operation"



3.3.8 Write Interrupted by a Precharge & DM

Random column access is allowed. A write recovery time(tWR) is required from the last data to precharge command. When precharge command is asserted, any residual data from the burst write cycle must be

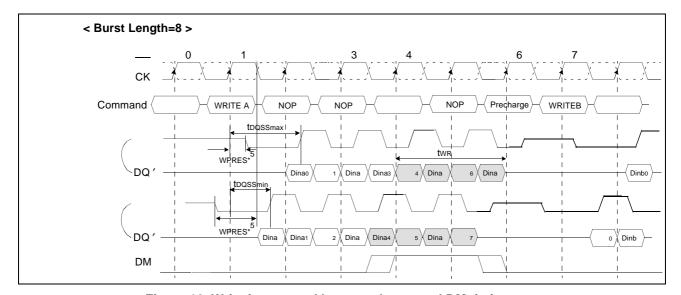


Figure 16. Write interrupted by a precharge and DM timing

Precharge timing for Write operations in DRAMs requires enough time to allow "write recovery" which is the

SDRAM, a timing parameter, tWR, is used to indicate the required amount of time between the last valid write operation and a Precharge command to the same bank.

the address is sampled by the input clock. Inside the SDRAM, the data path is eventually synchronized with the address path by switching clock domains from the data strobe clock domain to the input clock domain.

write recovery parameter must reference only the clock domain that is used to time the internal write operation, i.e., the input clock domain.

ends on the rising clock edge that strobes in the precharge command.

- 1. For the earliest possible Precharge command following a Write burst without interrupting the burst, the
- 2. When a precharge command interrupts a Write burst operation, the data mask pin, DM, is used to mask input data during the time between the last valid write data and the rising clock edge on which the

The minimum time for write recovery is defined by tWR.



- 3. For a Write with autoprecharge command, a new Bank Activate command may be issued to the same bank after tWR+tRP where tWR+tRP starts on the falling DQS edge that strobed in the last valid data and ends on the rising clock edge that strobes in the Bank Activate command. During write with autoprecharge, the initiation of the internal precharge occurs at the same time as the earliest possible external Precharge command without interrupting the Write burst as described in 1 above.
- 4. In all cases, a Precharge operation cannot be initiated unless tRAS(min) [minimum Bank Activate to Precharge time] has been satisfied. This includes Write with autoprecharge commands where tRAS(min) must still be satisfied such that a Write with autoprecharge command has the same timing as a Write command followed by the earliest possible Precharge command which does not interrupt the burst.
- 5. Refer to "3.3.2 Burst write operation"

3.3.9 Burst Stop

The burst stop command is initiated by having RAS and CAS high with CS and WE low at the rising edge of the clock(CK). The burst stop command has the fewest restrictions making it the easiest method to use when terminating a burst read operation before it has been completed. When the burst stop command is issued during a burst read cycle, the pair of data and DQS(Data Strobe) go to a high impedance state after a delay which is equal to the CAS latency set in the mode register. The burst stop command, however, is not supported during a write burst operation.

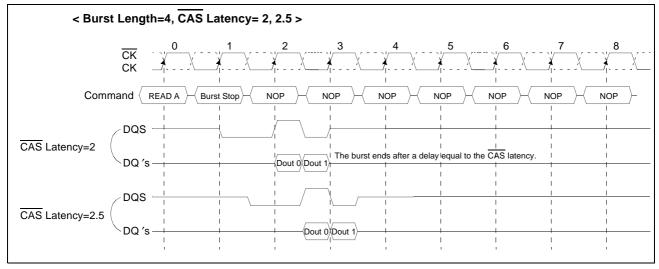


Figure 17. Burst stop timing

The Burst Stop command is a mandatory feature for DDR SDRAMs. The following functionality is required:

- 1. The BST command may only be issued on the rising edge of the input clock, CK.
- 2. BST is only a valid command during Read bursts.
- 3. BST during a Write burst is undefined and shall not be used.
- 4. BST applies to all burst lengths.
- 5. BST is an undefined command during Read with autoprecharge and shall not be used.

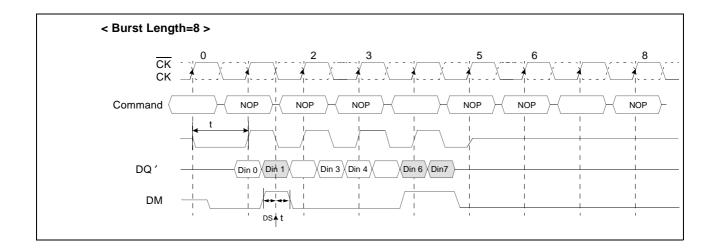


- 6. When terminating a burst Read command, the BST command must be issued L_{BST} cycles before the clock edge at which the output buffers are tristated, where L_{BST} CAS latency (CL) of 1.5, 2, CAS latencies are required by the DDR SDRAM standards, the others are
- 7. When the burst terminates, the DQ and DQS pins are tristated.

The BST command is not byte controllable and applies to all bits in the DQ data word and the(all) DQS pin(s).

3.3.10 DM masking

cycle. When the data mask is activated (DM high) during write operation, DDR SDRAM does not accept the corresponding data.(DM to data-mask latency is zero).





3.3.11 Read With Auto Precharge

If a read with auto-precharge command is initiated, the DDR SDRAM automatically enters the precharge operation BL/2 clock later from a read with auto-precharge command when tRAS(min) is satisfied. If not, the start point of precharge operation will be delayed until tRAS(min) is satisfied. Once the precharge operation has started the bank cannot be reactivated and the new command can not be asserted until the precharge time(tRP) has been satisfied.

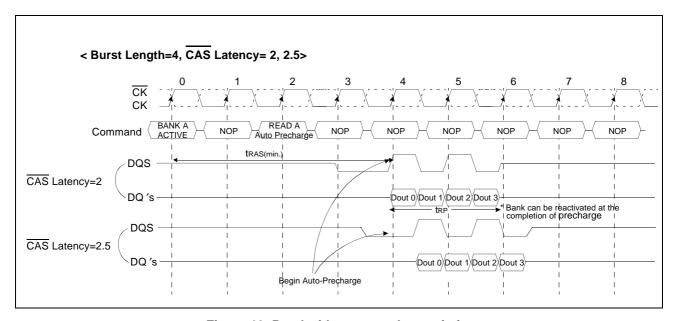


Figure 19. Read with auto precharge timing

When the Read with Auto precharge command is issued, new command can be asserted at 3,4 and 5 respectively as follows,

Asserted	F	or same Banl	k	For Different Bank			
command	3	4	5	3	4	5	
READ	READ + No AP*1	READ+ No AP	Illegal	Legal	Legal	Legal	
READ+AP	READ + AP	READ + AP	Illegal	Legal	Legal	Legal	
Active	Illegal	Illegal	Illegal	Legal	Legal	Legal	
Precharge	Legal	Legal	Illegal	Legal	Legal	Legal	

^{*1 :} AP = Auto Precharge

Table 6. Operating description when new command asserted while read with auto precharge is issued



If A10 is high when write command is issued, the write with auto-precharge function is performed. Any new command to the same bank should not be issued until the internal precharge is completed. The internal pre-

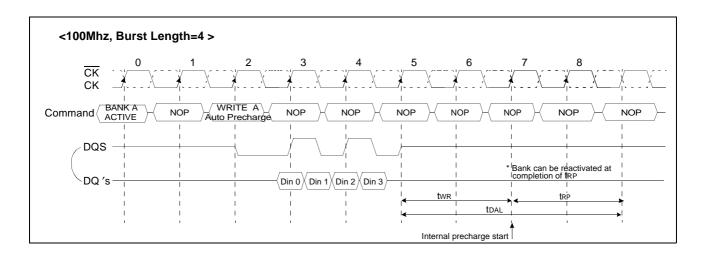


Figure 20. Write with auto precharge timing

Burst length = 4

Asserted			For same Ba	For Different Bank							
		4	5		7	8		4	5		7
WRITE	No AP*1	WRITE+ No AP		Illegal	Illegal		Legal	Legal		Legal	Legal
AP	WRITE+	WRITE+ AP		Illegal	Illegal		Legal	Legal		Legal	Legal
	Illegal	READ+NO *2	READ+NO	READ+ NO AP		Illegal	Illegal		Illegal	Legal	
READ+AP	Illegal	AP+DM	READ+	READ+ AP		Illegal	Illegal		Illegal	Legal	
Active	Illegal		Illegal	Illegal		Illegal	Legal		Legal	Legal	
Precharge	Illegal		Illegal	Illegal		Illegal	Legal		Legal	Legal	

^{*1 :} AP = Auto Precharge

: DM : Refer to " 3.3.7 Write Interrupted by a Read & DM " in page 25.

Table 7. Operating description when new command asserted while write with auto precharge is issued



3.3.13 Auto Refresh & Self Refresh

Auto Refresh

An auto refresh command is issued by having \overline{CS} , \overline{RAS} and \overline{CAS} held low with CKE and \overline{WE} high at the rising edge of the clock(CK). All banks must be precharged and idle for tRP(min) before the auto refresh command is applied. No control of the external address pins is required once this cycle has started because of the internal address counter. When the refresh cycle has completed, all banks will be in the idle state. A delay between the auto refresh command and the next activate command or subsequent auto refresh command must be greater than or equal to the tRFC(min).

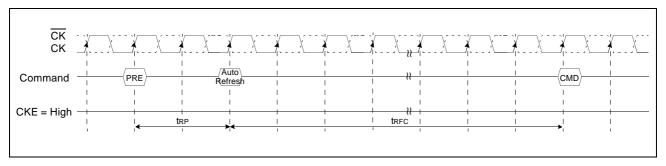


Figure 21. Auto refresh timing

Self Refresh

A self refresh command is defined by having \overline{CS} , \overline{RAS} , \overline{CAS} and CKE held low with \overline{WE} high at the rising edge of the clock(CK). Once the self refresh command is initiated, CKE must be held low to keep the device in self refresh mode. During the self refresh operation, all inputs except CKE are ignored. The clock is internally disabled during self refresh operation to reduce power consumption. The self refresh is exited by supplying stable clock input before returning CKE high, asserting deselect or NOP command and then asserting CKE high for longer than tXSR for locking of DLL.

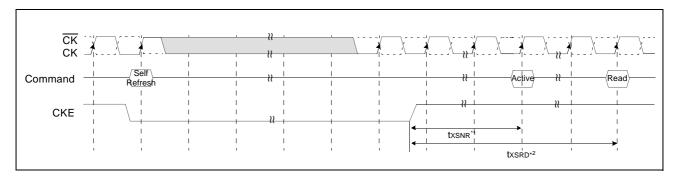


Figure 22. Self refresh timing

- 1. Exit self refresh to bank active command, a write command can be applied as far as tRCD is satisfied after any bank active command.
- 2. Exit self refresh to read command



3.3.14 Power down

The power down mode is entered when CKE is low and exited when CKE is high. Once the power down mode is initiated, all of the receiver circuits except clock, CKE and DLL circuit tree are gated off to reduce power consumption. All banks should be in idle state prior to entering the precharge power down mode and CKE should be set high at least 1tck+tlS prior to row active command. During power down mode, refresh operations cannot be performed, therefore the device cannot be remained in power down mode longer than the refresh period(Data retension time) of the device.

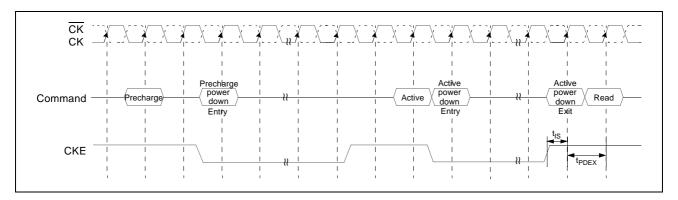


Figure 23. Power down entry and exit timing



4. Command Truth Table

(V=Valid, X=Don't Care, H=Logic High, L=Logic Low)

С	CKEn-1	CKEn	cs	RAS	CAS	WE	BA0,1	A10/AP	A11,A12 A9 ~ A0	Note		
Register	Extended M	RS	Н	Х	L	L	L	L	OP CODE			1, 2
Register	Mode Regis	ter Set	Н	Х	L	L	L	L	OP CODE			1, 2
	Auto Refres	h	Н	Н	L	L	L	Н		Х		3
Refresh	0.11	Entry	'''	L		L	_	''		^		3
Kellesii	Self Refresh	Exit	L	Н	L	Н	Н	Н		Х		3
		LXII	_		Н	Х	Х	Х		Α		3
Bank Active & Rov	v Addr.		Н	Х	L	L	Н	Н	V	Row A	Address	
Read &	Auto Precha	arge Disable	Н	Х	L	Н	L	Н	V	L	Column Address	4
Column Address	Auto Precha	arge Enable	П	^	_	""	_	''	v	Н		4
Write &	Auto Precha	arge Disable	Н	Х	L	Н	L	L	V	L	Column	4
Column Address Auto Precharge E		arge Enable	'''	^		11	_	-		Н	Address	4, 6
Burst Stop			Н	Х	L	Н	Н	L		Х		7
Precharge	Bank Select	ion	- н х	~	L	L	Н	L	V	L	Х	
1 recharge	All Banks			^	_	_			Х	Н	^	5
		Entry	Н	L	Н	Х	Х	Х				
Active Power Dow	n	Lilliy	'''	_	L	V	V	V		Χ		
		Exit	L	Н	Х	Х	Х	Х	1			
		Entry	Н	L	Н	Х	Х	Х	X			
Procharge Power I	Down Mode	Littiy	'''	_	L	Н	Н	Н				
Frecharge Fower	Precharge Power Down Mode		L	Н	Н	Х	Х	Х		^		
		Exit	L		L	V	V	V				
DM	Н			Х				Х		8		
No operation (NOF	P) · Not define	Ч	Н	Х	Н	Х	Х	Х	V			9
140 operation (140)	, . Not donne	u	''	^	L	Н	Н	Н		Х		

Table 8. Command truth table

- 1. OP Code: Operand Code. A0 ~ A11 & BA0 ~ BA1: Program keys. (@EMRS/MRS)
- 2.EMRS/ MRS can be issued only at all banks precharge state.
 - A new command can be issued 2 clock cycles after EMRS or MRS.
- 3. Auto refresh functions are same as the CBR refresh of DRAM.
 - The automatical precharge without row precharge command is meant by "Auto".
 - Auto/self refresh can be issued only at all banks precharge state.
- 4. BA0 ~ BA1: Bank select addresses.
 - If both BA0 and BA1 are "Low" at read, write, row active and precharge, bank A is selected.
 - If both BAo is "High" and BA1 is "Low" at read, write, row active and precharge, bank B is selected.
 - If both BAo is "Low" and BA1 is "High" at read, write, row active and precharge, bank C is selected.
- If both BA₀ and BA₁ are "High" at read, write, row active and precharge, bank D is selected. 5. If A₁₀/AP is "High" at row precharge, BA₀ and BA₁ are ignored and all banks are selected.
- 6. During burst write with auto precharge, new read/write command can not be issued.
 - Another bank read/write command can be issued after the end of burst.
- New row active of the associated bank can be issued at tRP after the end of burst. 7. Burst stop command is valid at every burst length.
- 8. DM sampled at the rising and falling edges of the DQS and Data-in are masked at the both edges (Write DM latency is 0).
- 9. This combination is not defined for any function, which means "No Operation(NOP)" in DDR SDRAM.



5. Functional Truth Table

Current State	cs	RAS	CAS	WE	Address	Command	Action
PRECHARGE	L	Н	Н	L	X	Burst Stop	ILLEGAL*2
STANDBY	L	Н	L	Х	BA, CA, A10 READ/WRITE II		ILLEGAL*2
	L	L	Н	Н	BA, RA	Active	Bank Active, Latch RA
	L	L	Н	L	BA, A10	PRE/PREA	ILLEGAL*4
	L	L	L	Н	X	Refresh	AUTO-Refresh*5
	L	L	L	L	Op-Code, Mode-Add	MRS	Mode Register Set*5
ACTIVE	L	Н	Н	L	Х	Burst Stop	NOP
STANDBY	L	Н	L	Н	BA, CA, A10	READ/READA	Begin Read, Latch CA, Determine Auto-Precharge
	L	Н	L	L	BA, CA, A10	WRITE/WRITEA	Begin Write, Latch CA, Determine Auto-Precharge
	L	L	Н	Η	BA, RA	Active	Bank Active/ILLEGAL*2
	L	L	Н	L	BA, A10	PRE/PREA	Precharge/Precharge All
	L	L	L	Н	X	Refresh	ILLEGAL
	L	L	L	L	Op-Code, Mode-Add	MRS	ILLEGAL
READ	L	Н	Н	Ш	X	Burst Stop	Terminate Burst
	L	Н	L	Н	BA, CA, A10	READ/READA	Terminate Burst, Latch CA, Begin New Read, Determine Auto-Precharge*3
	L	Н	L	L	BA, CA, A10	WRITE/WRITEA	ILLEGAL
	L	L	Н	Н	BA, RA	Active	Bank Active/ILLEGAL*2
	L	L	Н	L	BA, A10	PRE/PREA	Terminate Burst, Precharge
	L	L	L	Н	X	Refresh	ILLEGAL
	L	L	L	L	Op-Code, Mode-Add	MRS	ILLEGAL

Table 9-1. Functional truth table



Current State	cs	RAS	CAS	WE	Address	Command	Action
WRITE	L	Н	Н	L	X	Burst Stop	ILLEGAL
	L	Н	L	Н	BA, CA, A10	READ/READA	Terminate Burst With DM=High, Latch CA, Begin Read, Deter- mine Auto-Precharge*3
	L	Н	L	L	BA, CA, A10	WRITE/WRITEA	Terminate Burst, Latch CA, Begin new Write, Determine Auto-Precharge*3
	L	L	Н	Η	BA, RA	Active	Bank Active/ILLEGAL*2
	L	L	Н	L	BA, A10	PRE/PREA	Terminate Burst With DM=High, Precharge
	L	L	L	Η	X	Refresh	ILLEGAL
	L	L	L	L	Op-Code, Mode-Add	MRS	ILLEGAL
READ with	L	Н	Н	L	X	Burst Stop	ILLEGAL
AUTO PRECHARGE ^{*6}	L	Н	L	Н	BA, CA, A10	READ/READA	*6
(READA)	L	Н	L	L	BA, CA, A10	WRITE/WRITEA	ILLEGAL
	L	L	Н	Н	BA, RA	Active	*6
	L	L	Н	L	BA, A10	PRE/PREA	*6
	L	L	L	Η	X	Refresh	ILLEGAL
	L	L	L	L	Op-Code, Mode-Add	MRS	ILLEGAL
WRITE with	L	Н	Н	L	X	Burst Stop	ILLEGAL
AUTO RECHARGE ^{*7}	L	Н	L	Η	BA, CA, A10	READ/READA	*7
(WRITEA)	L	Н	L	L	BA, CA, A10	WRITE/WRITEA	*7
	L	L	Н	Η	BA, RA	Active	*7
	L	L	Н	L	BA, A10	PRE/PREA	*7
	L	L	L	Н	X	Refresh	ILLEGAL
	L	L	L	L	Op-Code, Mode-Add	MRS	ILLEGAL

Table 9-2. Functional truth table



Current State	cs	RAS	CAS	WE	Address	Command	Action
PRECHARG-	L	Н	Н	L	X	Burst Stop	ILLEGAL*2
ING (DURING tRP)	L	Н	L	Х	BA, CA, A10	READ/WRITE	ILLEGAL*2
	L	L	Н	Н	BA, RA	Active	ILLEGAL*2
	L	L	Н	┙	BA, A10	PRE/PREA	NOP*4(Idle after tRP)
	L	L	L	Н	X	Refresh	ILLEGAL
	L	L	L	L	Op-Code, Mode-Add	MRS	ILLEGAL
ROW	L	Н	Н	L	X	Burst Stop	ILLEGAL*2
ACTIVATING	L	Н	L	Χ	BA, CA, A10	READ/WRITE	ILLEGAL*2
(FROM ROW ACTIVE TO	L	L	Н	Н	BA, RA	Active	ILLEGAL*2
tRCD)	L	L	Н	L	BA, A10	PRE/PREA	ILLEGAL*2
(INCD)	L	L	L	Η	X	Refresh	ILLEGAL
	L	L	L	L	Op-Code, Mode-Add	MRS	ILLEGAL
WRITE	L	Н	Н	L	X	Burst Stop	ILLEGAL*2
RECOVERING	L	Н	L	Н	BA, CA, A10	READ	ILLEGAL*2
(DURING tWR OR tCDLR)	L	Н	L	L	BA, CA, A10	WRITE	WRITE
OT TOBER	L	L	Н	Η	BA, RA	Active	ILLEGAL*2
	L	L	Н	L	BA, A10	PRE/PREA	ILLEGAL*2
	L	L	L	Н	X	Refresh	ILLEGAL
	L	L	L	L	Op-Code, Mode-Add	MRS	ILLEGAL

Table 9-3. Functional truth table



Current State	cs	RAS	CAS	WE	Address	Command	Action
RE-	L	Н	Н	L	X	Burst Stop	ILLEGAL
FRESHING	L	Н	L	Х	BA, CA, A10	READ/WRITE	ILLEGAL
	L	L	Н	Н	BA, RA	Active	ILLEGAL
	L	L	Н	L	BA, A10	PRE/PREA	ILLEGAL
	L	L	L	Η	Х	Refresh	ILLEGAL
	L	L	L	L	Op-Code, Mode-Add	MRS	ILLEGAL
MODE	L	Н	Н	L	X	Burst Stop	ILLEGAL
REGISTER SETTING	L	Н	L	Χ	BA, CA, A10	READ/WRITE	ILLEGAL
02111110	L	L	Н	Η	BA, RA	Active	ILLEGAL
	L	L	Н	L	BA, A10	PRE/PREA	ILLEGAL
	L	L	L	Н	X	Refresh	ILLEGAL
	L	L	L	L	Op-Code, Mode-Add	MRS	ILLEGAL

Table 9-4. Functional truth table



Current State	CKE n-1	CKE n	cs	RAS	CAS	WE	Add	Action
SELF-	L	Н	Н	Х	Х	Х	Х	Exit Self-Refresh
REFRESHING*8	L	Н	L	Н	Н	Н	Х	Exit Self-Refresh
	L	Н	L	Н	Н	L	Х	ILLEGAL
	L	Н	L	Н	L	Х	Х	ILLEGAL
	L	Н	L	L	Х	Х	Х	ILLEGAL
	L	L	Х	Х	Х	Х	Х	NOPeration(Maintain Self-Refresh)
POWER	L	Н	Х	Х	Х	Χ	Х	Exit Power Down(Idle after tpdex)
DOWN	L	L	Х	Х	Х	Х	Х	NOPeration(Maintain Power Down)
ALL BANKS	Н	Н	Х	Х	Х	Х	Х	Refer to Function True Table
IDLE*9	Н	L	L	L	L	Н	Х	Enter Self-Refresh
	Н	L	Н	Х	Х	Х	Х	Enter Power Down
	Н	L	L	Н	Н	Н	Х	Enter Power Down
	Н	L	┙	Н	Н	┙	Χ	ILLEGAL
	Н	L	L	Н	L	Х	Х	ILLEGAL
	Н	L	L	L	Х	Х	Х	ILLEGAL
	L	Х	Х	Х	Х	Х	Х	Refer to Current State=Power Down
ANY STATE	Н	Н	Х	Х	Х	Χ	Х	Refer to Function Truth Table
other than								
listed above								

Table 9-5. Functional truth table

ABBREVIATIONS:

H=High Level, L=Low level, X=Don't Care

Note:

- 1. All entries assume that CKE was High during the preceding clock cycle and the current clock cycle.
- 2. ILLEGAL to bank in specified state; function may be legal in the bank indicated by BA, depending on the state of that bank.
- 3. Must satisfy bus contention, bus turn around and write recovery requirements.
- 4. NOP to bank precharging or in idle sate. May precharge bank indicated by BA.
- 5. ILLEGAL if any bank is not idle.
- 6. Refer to "3.3.11 Read with Auto Precharge" in page 29 for detailed information.
- 7. Refer to "3.3.12 Write with Auto Precharge" in page 30 for detailed information.
- 8. CKE Low to High transition will re-enable CK, $\overline{\text{CK}}$ and other inputs asynchronously. A minimum setup time must be satisfied before issuing any command other than EXIT.
- 9. Power-Down and Self-Refresh can be entered only from All Bank Idle state.

ILLEGAL = Device operation and/or data integrity are not guaranteed.



6. Absolute Maximum Rating

Parameter	Symbol	Value	Unit
Voltage on any pin relative to V _{SS}	V _{IN} , V _{OUT}	-0.5 ~ 3.6	V
Voltage on V_{DD} & V_{DDQ} supply relative to V_{SS}	V_{DD} , V_{DDQ}	-1.0 ~ 3.6	V
Storage temperature	T _{STG}	-55 ~ +150	°C
Power dissipation	P _D	1.5	W
Short circuit current	I _{OS}	50	mA

 ${f Note}$: Permanent device damage may occur if ABSOLUTE MAXIMUM RATINGS are exceeded.

Functional operation should be restricted to recommend operation condition.

Exposure to higher than recommended voltage for extended periods of time could affect device reliability.

Table 10. Absolute maximum ratings

7. DC Operating Conditions & Specifications

7.1 DC Operating Conditions

Recommended operating conditions(Voltage referenced to Vss=0V, Ta=0 to 70°C)

Parameter	Symbol	Min	Max	Unit	Note
Supply voltage(for device with a nominal VDD of 2.5V)	VDD	2.3	2.7		
I/O Supply voltage	VDDQ	2.3	2.7	V	
I/O Reference voltage	VREF	VDDQ/2-50mV	VDDQ/2+50mV	V	1
I/O Termination voltage(system)	V _{TT}	VREF-0.04	VREF+0.04	V	2
Input logic high voltage	VIH(DC)	VREF+0.15	VDDQ+0.3	V	4
Input logic low voltage	VIL(DC)	-0.3	VREF-0.15	V	4
Input Voltage Level, CK and CK inputs	VIN(DC)	-0.3	VDDQ+0.3	V	
Input Differential Voltage, CK and CK inputs	VID(DC)	0.3	VDDQ+0.6	V	3
Input crossing point voltage, CK and CK inputs	VIX(DC)	1.15	1.35	V	5
Input leakage current	lı	-2	2	uA	
Output leakage current	loz	-5	5	uA	
Output High Current(Normal strengh driver) ;V _{OUT} = V _{TT} + 0.84V	Юн	-16.8		mA	
Output High Current(Normal strengh driver) ;V _{OUT} = V _{TT} - 0.84V	loL	16.8		mA	
Output High Current(Half strengh driver) ;V _{OUT} = V _{TT} + 0.45V	Юн	-9		mA	
Output High Current(Half strengh driver) ;V _{OUT} = V _{TT} - 0.45V	loL	9		mA	

Table 11. DC operating condition



- Notes 1. Includes ± 25mV margin for DC offset on VREF, and a combined total of ± 50mV margin for all AC noise and DC offset on VREF, bandwidth limited to 20MHz. The DRAM must accommodate DRAM current spikes on VREF and internal DRAM noise coupled TO VREF, both of which may result in VREF noise. VREF should be de-coupled with an inductance of ≤ 3nH.
 - 2.V_{TT} is not applied directly to the device. V_{TT} is a system supply for signal termination resistors, is expected to be set equal to VREF, and must track variations in the DC level of VREF
 - 3. VID is the magnitude of the difference between the input level on CK and the input level on $\overline{\text{CK}}$.
 - 4. These parameters should be tested at the pin on actual components and may be checked at either the pin or the pad in simulation. The AC and DC input specifications are relative to a VREF envelop that has been bandwidth limited to 200MHZ.
 - 5. The value of Vix is expected to equal 0.5*VDDQ of the transmitting device and must track variations in the dc level of the same.
 - 6. These charactericteristics obey the SSTL-2 class II standards.

7.2 DDR SDRAM SPEC Items and Test Conditions

Conditions	Symbol
Operating current - One bank Active-Precharge; tRC=tRCmin; DQ,DM and DQS inputs changing twice per clock cycle; address and control inputs changing once per clock cycle	IDD0
Operating current - One bank operation; One bank open, BL=4, Reads - Refer to the following page for detailed test condition	IDD1
Percharge power-down standby current; All banks idle; power - down mode; CKE = <vil(max); and="" dm<="" dq,dqs="" for="" td="" vin="Vref"><td>IDD2P</td></vil(max);>	IDD2P
Precharge Floating standby current; CS# > =VIH(min); All banks idle; CKE > = VIH(min); Address and other control inputs changing once per clock cycle; Vin = Vref for DQ,DQS and DM	IDD2F
Precharge Quiet standby current; CS# > = VIH(min); All banks idle; CKE > = VIH(min); Address and other control inputs stable with keeping >= VIH(min) or = <vil(max); ,dqs="" and="" dm<="" dq="" for="" td="" vin="Vref"><td>IDD2Q</td></vil(max);>	IDD2Q
Active power - down standby current; one bank active; power-down mode; CKE=< VIL (max); Vin = Vref for DQ,DQS and DM	IDD3P
Active standby current; CS# >= VIH(min); CKE>=VIH(min); one bank active; active - precharge; tRC=tRASmax; DQ, DQS and DM inputs changing twice per clock cycle; address and other control inputs changing once per clock cycle	IDD3N
Operating current - burst read; Burst length = 2; reads; continguous burst; One bank active; address and control inputs changing once per clock cycle; 50% of data changing at every burst; lout = 0 m A	IDD4R
Operating current - burst write; Burst length = 2; writes; continuous burst; One bank active address and control inputs changing once per clock cycle; DQ, DM and DQS inputs changing twice per clock cycle, 50% of input data changing at every burst	IDD4W
Auto refresh current; tRC = tRFC(min) - 8*tCK for DDR200 at 100Mhz, 10*tCK for DDR266A & DDR266B at 133Mhz; distributed refresh	IDD5
Self refresh current; CKE =< 0.2V; External clock should be on; tCK = 100Mhz for DDR200, 133Mhz for DDR266A & DDR266B	IDD6
Orerating current - Four bank operation; Four bank interleaving with BL=4 -Refer to the following page for detailed test condition	IDD7A



7.3 DDR SDRAM IDD spec table

 $(VDD=2.7V, T = 10^{\circ}C)$

		128	Mx4	k4 64Mx8			·
s	Symbol	TCA2/CB0 TCA0 TCA2/CB0		K4H510838M- TCA0 (DDR200)	Unit	Notes	
	IDD0	165	150	165	150	mA	
	IDD1	190	175	190	175	mA	
I	DD2P	6	5	6	5	mA	
	IDD2F	50	40	50	40	mA	
I	DD2Q	25	20	25	20	mA	
ı	DD3P	50	40	50	40	mA	
I	DD3N	95	80	95	80	mA	
I	DD4R	200	160	220	190	mA	
I	DD4W	220	180	250	220	mA	
	IDD5	310	290	310	290	mA	
IDD6	Normal	5	5	5	5	mA	
	Low power	3	3	3	3	mA	Optional
ı	DD7A	460	400	480	420	mA	

Table 13. DDR SDRAM IDD spec Table

< Detailed test conditions for DDR SDRAM IDD1 & IDD7 >

IDD1: Operating current: One bank operation

- 1. Only one bank is accessed with tRC(min), Burst Mode, Address and Control inputs on NOP edge are changing once per clock cycle. lout = 0mA
- 2. Timing patterns
 - DDR200(100Mhz, CL=2): tCK = 10ns, CL2, BL=4, tRCD = 2*tCK, tRAS = 5*tCK Read: A0 N R0 N N P0 N A0 N repeat the same timing with random address changing *50% of data changing at every burst
 DDR266B(133Mhz, CL=2.5): tCK = 7.5ns, CL=2.5, BL=4, tRCD = 3*tCK, tRC = 9*tCK, tRAS = 5*tCK
 - Read: A0 N N R0 N P0 N N N A0 N repeat the same timing with random address changing *50% of data changing at every burst DDR266A (133Mhz, CL=2): tCK = 7.5ns, CL=2, BL=4, tRCD = 3*tCK, tRC = 9*tCK, tRAS = 5*tCK
 - DDR266A (133Mhz, CL=2): tCK = 7.5ns, CL=2, BL=4, tRCD = 3*tCK, tRC = 9*tCK, tRAS = 5*tCK
 Read: A0 N N R0 N P0 N N N A0 N repeat the same timing with random address changing
 *50% of data changing at every burst

IDD7A: Operating current: Four bank operation

- 1. Four banks are being interleaved with tRC(min), Burst Mode, Address and Control inputs on NOP edge are not changing. lout = 0mA
- 2. Timing patterns
- DDR200(100Mhz, CL=2): tCK = 10ns, CL2, BL=4, tRRD = 2*tCK, tRCD= 3*tCK, Read with autoprecharge Read: A0 N A1 R0 A2 R1 A3 R2 A0 R3 A1 R0 repeat the same timing with random address changing *100% of data changing at every burst
- DDR266B(133Mhz, CL=2.5): tCK = 7.5ns, CL=2.5, BL=4, tRRD = 2*tCK, tRCD = 3*tCK Read with autoprecharge
- Read : A0 N A1 R0 A2 R1 A3 R2 N R3 A0 N A1 R0 $\,$ repeat the same timing with random address changing *100% of data changing at every burst
- DDR266A (133Mhz, CL=2): tCK = 7.5ns, CL2=2, BL=4, tRRD = 2*tCK, tRCD = 3*tCK,Read with autoprecharge Read: A0 N A1 R0 A2 R1 A3 R2 N R3 A0 N A1 R0 repeat the same timing with random address changing *100% of data changing at every burst

Legend: A=Activate, R=Read, W=Write, P=Precharge, N=NOP



8. AC Operating Conditions & Timming Specification

8.1 AC Operating Conditions

Parameter/Condition	Symbol	Min	Max	Unit	Note
Input High (Logic 1) Voltage, DQ, DQS and DM signals	VIH(AC)	VREF + 0.31		V	3
Input Low (Logic 0) Voltage, DQ, DQS and DM signals.	VIL(AC)		VREF - 0.31	V	3
Input Differential Voltage, CK and CK inputs	VID(AC)	0.7	VDDQ+0.6	V	1
Input Crossing Point Voltage, CK and CK inputs	VIX(AC)	0.5*VDDQ-0.2	0.5*VDDQ+0.2	V	2

Note

- 1. VID is the magnitude of the difference between the input level on CK and the input on $\overline{\text{CK}}$.
- 2. The value of V_{IX} is expected to equal 0.5^*V_{DDQ} of the transmitting device and must track variations in the DC level of the same.
- 3. These parameters should be tested at the pim on actual components and may be checked at either the pin or the pad in simulation. the AC and DC input specificatims are refation to a Vref envelope that has been bandwidth limited 20MHz.

Table 13. AC operating conditions



8.2 AC Overshoot/Undershoot specification

8.2.1 Overshoot/Undershoot specification for Address and Control Pins

Parameter	Specification	Notes
Maximum peak amplitude allowed for overshoot (See Figure 1):	1.6 V	1,2,3
Maximum peak amplitude allowed for undershoot (See Figure 1):	1.6 V	1,2,3
The area between the overshoot signal and VDD must be less than or equal to (See Figure 1):	4.5 V-ns	1,2,3
The area between the undershoot signal and GND must be less than or equal to (See Figure 1):	4.5 V-ns	1,2,3

Table 14. Overshoot/Undershoot specification for Address and Control Pins

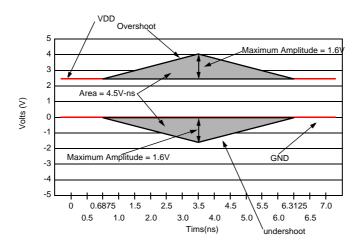


Figure 24. AC overshoot/Undershoot Definition

Notes:

- 1. This specification is intended for only DDR200, DDR266A and DDR266B devices.
- 2. This specification is intended for only devices with NO clamp protection
- 3. This compliance is to be verified by design only.



8.2.2 Overshoot/Undershoot specification for Data Pins

Parameter	Specification	Notes
Maximum peak amplitude allowed for overshoot (See Figure 2):	1.2 V	1,2,3
Maximum peak amplitude allowed for undershoot (See Figure 2):	1.2 V	1,2,3
The area between the overshoot signal and VDD must be less than or equal to (See Figure 2):	2.5 V-ns	1,2,3
The area between the undershoot signal and GND must be less than or equal to (See Figure 2):	2.5 V-ns	1,2,3

Table 15. Overshoot/Undershoot specification for Data Pins

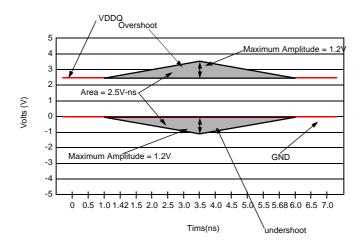


Figure 25. AC overshoot/Undershoot Definition

Notes:

- 1. This specification is intended for only DDR200, DDR266A and DDR266B devices.
- 2. This specification is intended for only devices with NO clamp protection
- 3. This compliance is to be verified by design only.



8.3 AC Timming Parameters & Specifications

Parameter	Symbol		CA2 (266A)		CB0 (266B)		CA0 R200)	Unit	Note
		Min	Max	Min	Max	Min	Max	1	
Row cycle time	tRC	65		65		70		ns	
Refresh row cycle time	tRFC	75		75		80		ns	
Row active time	tRAS	45	120K	45	120K	48	120K	ns	
RAS to CAS delay	tRCD	20		20		20		ns	
Row precharge time	tRP	20		20		20		ns	
Row active to Row active delay	tRRD	15		15		15		ns	
Write recovery time	tWR	15		15		15		ns	
Last data in to Read command	tWTR	1		1		1		tCK	
Col. address to Col. address delay	tCCD	1		1		1		tCK	
CL=2.0	.011	7.5	12	10	12	10	12	ns	5
Clock cycle time CL=2.5	tCK	7.5	12	7.5	12			ns	5
Clock high level width	tCH	0.45	0.55	0.45	0.55	0.45	0.55	tCK	
Clock low level width	tCL	0.45	0.55	0.45	0.55	0.45	0.55	tCK	
DQS-out access time from CK/CK	tDQSCK	-0.75	+0.75	-0.75	+0.75	-0.8	+0.8	ns	
Output data access time from CK/CK	tAC	-0.75	+0.75	-0.75	+0.75	-0.8	+0.8	ns	
Data strobe edge to ouput data edge	tDQSQ	-	0.5	-	0.5	-	0.6	ns	5
Read Preamble	tRPRE	0.9	1.1	0.9	1.1	0.9	1.1	tCK	
Read Postamble	tRPST	0.4	0.6	0.4	0.6	0.4	0.6	tCK	
CK to valid DQS-in	tDQSS	0.75	1.25	0.75	1.25	0.75	1.25	tCK	
DQS-in setup time	tWPRES	0		0		0		ns	2
DQS-in hold time	tWPRE	0.25		0.25		0.25		tCK	
DQS falling edge to CK rising-setup time	tDSS	0.2		0.2		0.2		tCK	
DQS falling edge from CK rising-hold time	tDSH	0.2		0.2		0.2		tCK	
DQS-in high level width	tDQSH	0.35		0.35		0.35		tCK	
DQS-in low level width	tDQSL	0.35		0.35		0.35		tCK	
DQS-in cycle time	tDSC	0.9	1.1	0.9	1.1	0.9	1.1	tCK	
Address and Control Input setup time(fast)	tIS	0.9		0.9		1.1		ns	6
Address and Control Input hold time(fast)	tIH	0.9		0.9		1.1		ns	6
Address and Control Input setup time(slow)	tIS	1.0		1.0		1.1		ns	6
Address and Control Input hold time(slow)	tIH	1.0		1.0		1.1		ns	6
Data-out high impedence time from CK/CK	tHZ	-0.75	+0.75	-0.75	+0.75	-0.8	+0.8	ns	
Data-out low impedence time from CK/CK	tLZ	-0.75	+0.75	-0.75	+0.75	-0.8	+0.8	ns	
Input Slew Rate(for input only pins)	tSL(I)	0.5		0.5		0.5		V/ns	6
Input Slew Rate(for I/O pins)	tSL(IO)	0.5		0.5		0.5		V/ns	7
Output Slew Rate(x4,x8)	tSL(O)	1.0	4.5	1.0	4.5	1.0	4.5	V/ns	10
Output Slew Rate Matching Ratio(rise to fall)	tSLMR	0.67	1.5	0.67	1.5	0.67	1.5		



Parameter	Symbol	-TC (DDR2		-TCI (DDR2		-TC/ (DDR:		Unit	Note
. a. amotor		Min	Max	Min	Max	Min	Max		
Mode register set cycle time	tMRD	15		15		16		ns	
DQ & DM setup time to DQS	tDS	0.5		0.5		0.6		ns	7,8,9
DQ & DM hold time to DQS	tDH	0.5		0.5		0.6		ns	7,8,9
Control & Address input pulse width	tIPW	2.2		2.2		2.5		ns	
DQ & DM input pulse width	tDIPW	1.75		1.75		2		ns	
Power down exit time	tPDEX	7.5		7.5		10		ns	
Exit self refresh to non-Read command	tXSNR	75		75		80		ns	4
Exit self refresh to read command	tXSRD	200		200		200		tCK	
Refresh interval time	tREFI	7.8		7.8		7.8		us	1
Output DQS valid window	tQH	tHP -tQHS	-	tHP -tQHS	-	tHP -tQHS	-	ns	5
Clock half period	tHP	tCLmin or tCHmin	-	tCLmin or tCHmin	-	tCLmin or tCHmin	-	ns	
Data hold skew factor	tQHS		0.75		0.75		0.8	ns	
DQS write postamble time	tWPST	0.4	0.6	0.4	0.6	0.4	0.6	tCK	3
Active to Read with Auto precharge command	tRAP	20		20		20			
Autoprecharge write recovery + Precharge time	tDAL	(tWR/tCK) + (tRP/tCK)		(tWR/tCK) + (tRP/tCK)		(tWR/tCK) + (tRP/tCK)		tCK	11

- 1. Maximum burst refresh cycle: 8
- 2. The specific requirement is that DQS be valid(High or Low) on or before this CK edge. The case shown(DQS going from High_Z to logic Low) applies when no writes were previously in progress on the bus. If a previous write was in progress, DQS could be High at this time, depending on tDQSS.
- 3. The maximum limit for this parameter is not a device limit. The device will operate with a great value for this parameter, but system performance (bus turnaround) will degrade accordingly.
- 4. A write command can be applied with tRCD satisfied after this command.
- 5. For registered DIMMs, tcL and tcH are ≥ 45% of the period including both the half period jitter (tJIT(HP)) of the PLL and the half period jitter due to crosstalk (tJIT(crosstalk)) on the DIMM.
- 6. Input Setup/Hold Slew Rate Derating

Input Setup/Hold Slew Rate	ΔtIS	ΔtlH
(V/ns)	(ps)	(ps)
0.5	0	0
0.4	+50	+50
0.3	+100	+100

This derating table is used to increase t_{IS}/t_{IH} in the case where the input slew rate is below 0.5V/ns. Input setup/hold slew rate based on the lesser of AC-AC slew rate and DC-DC slew rate.

7. I/O Setup/Hold Slew Rate Derating

I/O Setup/Hold Slew Rate	ΔtDS	ΔtDH
(V/ns)	(ps)	(ps)
0.5	0	0
0.4	+75	+75
0.3	+150	+150

This derating table is used to increase t_{DS}/t_{DH} in the case where the I/O slew rate is below 0.5V/ns. I/O setup/hold slew rate based on the lesser of AC-AC slew rate and DC-DC slew rate.



8. I/O Setup/Hold Plateau Derating

I/O Input Level	ΔtDS	ΔtDH
(mV)	(ps)	(ps)
± 280	+50	+50

This derating table is used to increase tDS/tDH in the case where the input level is flat below VREF \pm 310mV for a duration of up to 2ns

9. I/O Delta Rise/Fall Rate(1/slew-rate) Derating

Delta Rise/Fall Rate	ΔtDS	ΔtDH
(ns/V)	(ps)	(ps)
0	0	0
±0.25	+50	+50
±0.5	+100	+100

This derating table is used to increase tDS/tDH in the case where the DQ and DQS slew rates differ. The Delta Rise/Fall Rate is calated as 1/SlewRate1-1/SlewRate2. For example, if slew rate 1 = 5V/ns and slew rate 2 = .4V/ns then the Delta Rise/Fall Rate =-0/5ns/V. Input S/H slew rate based on larger of AC-AC delta rise/fall rate and DC-DC delta rise/fall rate.

<Reference>

The following table specifies derating values for the specifications listed if the single-ended clock skew rate is less than 1.0V/ns.

CK slew rate (Single ended)	∆tlH/tIS (ps)	ΔtDSS/tDSH (ps)	ΔtAC/tDQSCK (ps)	∆tLZ(min) (ps)	∆tHZ(max) (ps)
1.0V/ns	0	0	0	0	0
0.75V/ns	+50	+50	+50	-50	+50
0.5V/ns	+100	+100	+100	-100	+100

Table 17. AC timing parameters and specifications



^{10.} This parameter is fir system simulation purpose. It is guranteed by design.

^{11.} For each of the terms, if not already an integer, round to the next highest integer. tCK is actual to the system clock cycle time.

9. AC Operating Test Conditions

(VDD=2.5V, VDDQ=2.5V, TA= 0 to 70° C)

Parameter	Value	Unit	Note
Input reference voltage for Clock	0.5 * VDDQ	V	
Input signal maximum peak swing	1.5	V	
Input signal minimum slew rate (for imput only)	0.5	V/ns	
Input slew rate (I/O pins)	0.5	V/ns	
Input Levels(VIH/VIL)	VREF+0.31/VREF-0.31	V	
Input timing measurement reference level	VREF	V	
Output timing measurement reference level	Vtt	V	
Output load condition	See Load Circuit		

Table 17. AC operating test conditions

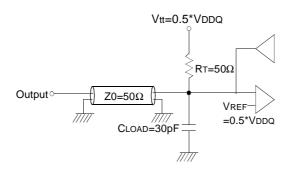


Figure 26. Output Load Circuit (SSTL_2)

10. Input/Output Capacitance

(VDD=2.5, VDDQ=2.5V, TA= 25°C, f=1MHz)

Parameter	Symbol	Min	Max	Delta Cap(max)	Unit
Input capacitance (A0 ~ A11, BA0 ~ BA1, CKE, CS, RAS, CAS, WE)	CIN1	2	3.0	0.5	pF
Input capacitance(CK, CK)	CIN2	2	3.0	0.25	pF
Data & DQS input/output capacitance	Соит	4.0	5.0	0.5	pF
Input capacitance(DM)	CIN3	4.0	5.0	0.5	pF

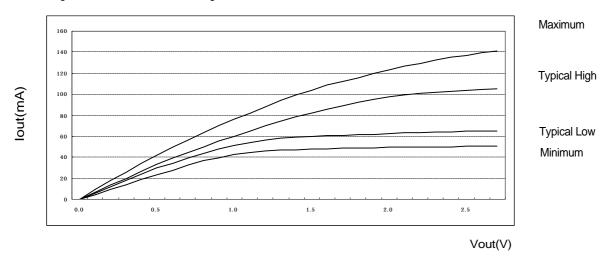
Table 18. Input/output capacitance



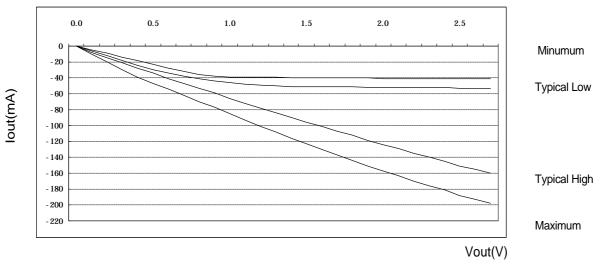
11. IBIS: I/V Characteristics for Input and Output Buffers

11.1 Normal strength driver

- 1. The full variation in driver pulldown current from minimum to maximum process, temperature, and voltage will lie within the outer bounding lines of the V-I curve of Figure a.
- 2. The full variation in driver pulldown current from minimum to maximum process, temperature and voltage will lie within the outer bounding lines the of the V-I curve of Figure a.



- 3. The full variation in driver pullup current from minimum to maximun process, temperature, and voltage will lie within the outer bounding lines of the V-I curve of Figure b.
- 4. The variation in the driver pullup current at nominal temperature and voltage is expected, but not guaranteed, to lie within the inner boungding lines of the V-I curve of Figure b as



- 5. The full variation in the ratio of the maximum to minimum pullup and pulldown current will not exceed 1.7, for device drain to source voltage from 0 to VDDQ/2
- 6. The Full variation in the ratio of the nominal pullup to pulldown current should be unity ±10%, for device drain to source voltages from 0 to VDDQ/2

Figure 27. I/V characteristics for input/output buffers:Pull up(above) and pull down(below)



	Pulldown Current (mA)				pullup Cu	rrent (mA)		
Voltage (V)	Typical Low	Typical High	Minimum	Maximum	Typical Low	Typical High	Minimum	Maximum
0.1	6.0	6.8	4.6	9.6	-6.1	-7.6	-4.6	-10.0
0.2	12.2	13.5	9.2	18.2	-12.2	-14.5	-9.2	-20.0
0.3	18.1	20.1	13.8	26.0	-18.1	-21.2	-13.8	-29.8
0.4	24.1	26.6	18.4	33.9	-24.0	-27.7	-18.4	-38.8
0.5	29.8	33.0	23.0	41.8	-29.8	-34.1	-23.0	-46.8
0.6	34.6	39.1	27.7	49.4	-34.3	-40.5	-27.7	-54.4
0.7	39.4	44.2	32.2	56.8	-38.1	-46.9	-32.2	-61.8
0.8	43.7	49.8	36.8	63.2	-41.1	-53.1	-36.0	-69.5
0.9	47.5	55.2	39.6	69.9	-41.8	-59.4	-38.2	-77.3
1.0	51.3	60.3	42.6	76.3	-46.0	-65.5	-38.7	-85.2
1.1	54.1	65.2	44.8	82.5	-47.8	-71.6	-39.0	-93.0
1.2	56.2	69.9	46.2	88.3	-49.2	-77.6	-39.2	-100.6
1.3	57.9	74.2	47.1	93.8	-50.0	-83.6	-39.4	-108.1
1.4	59.3	78.4	47.4	99.1	-50.5	-89.7	-39.6	-115.5
1.5	60.1	82.3	47.7	103.8	-50.7	-95.5	-39.9	-123.0
1.6	60.5	85.9	48.0	108.4	-51.0	-101.3	-40.1	-130.4
1.7	61.0	89.1	48.4	112.1	-51.1	-107.1	-40.2	-136.7
1.8	61.5	92.2	48.9	115.9	-51.3	-112.4	-40.3	-144.2
1.9	62.0	95.3	49.1	119.6	-51.5	-118.7	-40.4	-150.5
2.0	62.5	97.2	49.4	123.3	-51.6	-124.0	-40.5	-156.9
2.1	62.9	99.1	49.6	126.5	-51.8	-129.3	-40.6	-163.2
2.2	63.3	100.9	49.8	129.5	-52.0	-134.6	-40.7	-169.6
2.3	63.8	101.9	49.9	132.4	-52.2	-139.9	-40.8	-176.0
2.4	64.1	102.8	50.0	135.0	-52.3	-145.2	-40.9	-181.3
2.5	64.6	103.8	50.2	137.3	-52.5	-150.5	-41.0	-187.6
2.6	64.8	104.6	50.4	139.2	-52.7	-155.3	-41.1	-192.9
2.7	65.0	105.4	50.5	140.8	-52.8	-160.1	-41.2	-198.2

Table 19. Pull down and pull up current values

Temperature (Tambient)

Typical 25°C Minimum 70°C Maximum 0°C

Vdd/Vddq

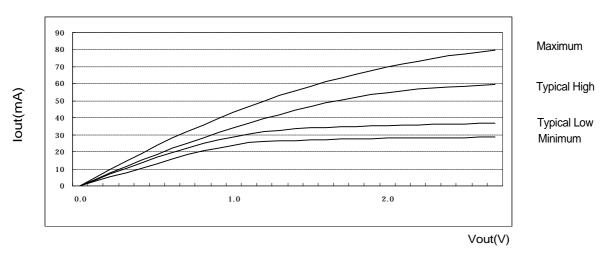
Typical 2.5V Minimum 2.3V Maximum 2.7V

The above characteristics are specified under best, worst and normal process variation/conditions

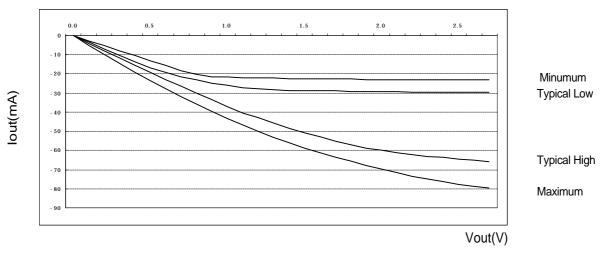


11.2 Weak strength driver

- 1. The nominal pulldown V-I curve for DDR SDRAM devices will be within the inner bounding lines of the V-I curve of Figure a.
- 2. The full variation in driver pulldown current from minimum to maximum process, temperature and voltage will lie within the outer bounding lines the of the V-I curve of Figure a.



- 3. Thenominal pullup V-I curve for DDR SDRAM devices will be within the inner bounding lines of the V-I curve of below Figure b.
- 4. The Full variation in driver pullup current from minimum to maximum process, temperature and voltage will lie within the outer bounding lines of the V-I curve of Figrue b.



- 5. The full variation in the ratio of the maximum to minimum pullup and pulldown current will not exceed 1.7, for device drain to source voltage from 0 to VDDQ/2
- 6. The Full variation in the ratio of the nominal pullup to pulldown current should be unity ±10%, for device drain to source voltages from 0 to VDDQ/2

Figure 28. I/V characteristics for input/output buffers:Pull up(above) and pull down(below)



	Pulldown Current (mA)					pullup Cu	rrent (mA)	
Voltage (V)	Typical Low	Typical High	Minimum	Maximum	Typical Low	Typical High	Minimum	Maximum
0.1	3.4	3.8	2.6	5.0	-3.5	-4.3	-2.6	-5.0
0.2	6.9	7.6	5.2	9.9	-6.9	-8.2	-5.2	-9.9
0.3	10.3	11.4	7.8	14.6	-10.3	-12.0	-7.8	-14.6
0.4	13.6	15.1	10.4	19.2	-13.6	-15.7	-10.4	-19.2
0.5	16.9	18.7	13.0	23.6	-16.9	-19.3	-13.0	-23.6
0.6	19.6	22.1	15.7	28.0	-19.4	-22.9	-15.7	-28.0
0.7	22.3	25.0	18.2	32.2	-21.5	-26.5	-18.2	-32.2
0.8	24.7	28.2	20.8	35.8	-23.3	-30.1	-20.4	-35.8
0.9	26.9	31.3	22.4	39.5	-24.8	-33.6	-21.6	-39.5
1.0	29.0	34.1	24.1	43.2	-26.0	-37.1	-21.9	-43.2
1.1	30.6	36.9	25.4	46.7	-27.1	-40.3	-22.1	-46.7
1.2	31.8	39.5	26.2	50.0	-27.8	-43.1	-22.2	-50.0
1.3	32.8	42.0	26.6	53.1	-28.3	-45.8	-22.3	-53.1
1.4	33.5	44.4	26.8	56.1	-28.6	-48.4	-22.4	-56.1
1.5	34.0	46.6	27.0	58.7	-28.7	-50.7	-22.6	-58.7
1.6	34.3	48.6	27.2	61.4	-28.9	-52.9	-22.7	-61.4
1.7	34.5	50.5	27.4	63.5	-28.9	-55.0	-22.7	-63.5
1.8	34.8	52.2	27.7	65.6	-29.0	-56.8	-22.8	-65.6
1.9	35.1	53.9	27.8	67.7	-29.2	-58.7	-22.9	-67.7
2.0	35.4	55.0	28.0	69.8	-29.2	-60.0	-22.9	-69.8
2.1	35.6	56.1	28.1	71.6	-29.3	-61.2	-23.0	-71.6
2.2	35.8	57.1	28.2	73.3	-29.5	-62.4	-23.0	-73.3
2.3	36.1	57.7	28.3	74.9	-29.5	-63.1	-23.1	-74.9
2.4	36.3	58.2	28.3	76.4	-29.6	-63.8	-23.2	-76.4
2.5	36.5	58.7	28.4	77.7	-29.7	-64.4	-23.2	-77.7
2.6	36.7	59.2	28.5	78.8	-29.8	-65.1	-23.3	-78.8
2.7	36.8	59.6	28.6	79.7	-29.9	-65.8	-23.3	-79.7

Table 20. Pull down and pull up current values

Temperature (Tambient)

 $\begin{array}{ll} \text{Typical} & 25^{\circ}\text{C} \\ \text{Minimum} & 70^{\circ}\text{C} \\ \text{Maximum} & 0^{\circ}\text{C} \end{array}$

Vdd/Vddq

Typical 2.5V Minimum 2.3V Maximum 2.7V

The above characteristics are specified under best, worst and normal process variation/conditions

